

WHAT IS CLAIMED IS:

1. An image pickup apparatus capable of performing an image pickup with pattern projection on an object to obtain three-dimensional information on the object, and an image pickup without pattern projection, comprising:

an exposure level determination section configured to determine a predetermined exposure level needed by an image pickup device of the image pickup apparatus;

and

a shutter speed determination section configured to determine a first shutter speed to achieve the predetermined exposure level determined by the exposure level determination section in the image pickup without pattern projection, and a second shutter speed not slower than the first shutter speed, wherein

the image pickup with pattern projection is conducted by use of the second shutter speed.

2. The apparatus according to claim 1, wherein the second shutter speed is a shutter speed faster than the first shutter speed.

3. The apparatus according to claim 1, wherein the image pickup apparatus is a stereographic image pickup apparatus capable of picking up images of the object from a plurality of view points, and the pattern is a random dot pattern.

4. The apparatus according to claim 1, wherein

the pattern is projected by use of light emitted from a flash emission source.

5. The apparatus according to claim 1, wherein the shutter speed determination section determines the second shutter speed so as to take a time longer than a time in which the pattern is projected.

6. The apparatus according to claim 1, further comprising an image pickup aperture adjustment section configured to adjust an image pickup aperture, wherein
10 the image pickup aperture adjustment section adjusts the image pickup aperture to have the predetermined exposure level at the second shutter speed when the image pickup with pattern projection is conducted.

15 7. The apparatus according to claim 1, wherein the shutter speed determination section determines at least one of the second shutter speed and the image pickup aperture of the image pickup apparatus on the basis of luminance information on the object when the
20 pattern is projected and of the predetermined exposure level.

8. The apparatus according to claim 1, wherein the shutter speed determination section determines the first shutter speed on the basis of an image pickup aperture determined in accordance with a desired field depth set by an operator and of the predetermined exposure level.
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9. The apparatus according to claim 8, wherein
the image pickup aperture is an aperture not smaller
than an aperture that can achieve the predetermined
exposure level in the image pickup with pattern
projection on the assumption that the shutter speed of
the image pickup apparatus takes the same time as a
projection time of the pattern.

10. The apparatus according to claim 1, further
comprising an illumination section configured to
illuminate the object during the image pickup, wherein
the image pickup apparatus picks up an image of
the object illuminated by the illumination section by
use of a shutter speed not slower than the second
shutter speed.

15 11. An image pickup apparatus comprising:
an image pickup section, including an image pickup
device, configured to pick up an image of an object;
a photometric section configured to measure
luminance information on the object;
20 a projection section configured to project a
pattern on the object during the image pickup, the
image pickup apparatus being capable of performing an
image pickup by the image pickup section with pattern
projection by the projection section on the object to
obtain three-dimensional information on the object, and
25 an image pickup by the image pickup section without
pattern projection;

an exposure level determination section configured to determine a predetermined exposure level needed by the image pickup device; and

5 a shutter speed determination section configured to determine a first shutter speed to achieve the predetermined exposure level determined by the exposure level determination section in the image pickup without pattern projection, and a second shutter speed not slower than the first shutter speed, on the basis of
10 luminance information on the object measured by the photometric section, wherein

the image pickup section conducts the image pickup with pattern projection by the projection section by use of the second shutter speed.

15 12. A method of an image pickup for an image pickup apparatus capable of performing an image pickup with pattern projection on an object to obtain three-dimensional information on the object, and an image pickup without pattern projection, the method comprising:

determining a predetermined exposure level;
determining a first shutter speed to achieve the predetermined exposure level in the image pickup without pattern projection, and a second shutter speed not slower than the first shutter speed; and

conducting the image pickup with pattern projection by use of the second shutter speed.

13. A method of controlling an image pickup apparatus capable of performing an image pickup with pattern projection on an object to obtain three-dimensional information on the object, and an image pickup without pattern projection, the method comprising:

determining a predetermined exposure level; and
determining a first shutter speed to achieve
the predetermined exposure level in the image pickup
without pattern projection, and a second shutter speed
not slower than the first shutter speed, wherein
the second shutter speed is used when the image
pickup with pattern projection is conducted.

14. An image pickup apparatus capable of
performing an image pickup with pattern projection on
an object to obtain three-dimensional information on
the object, and an image pickup without pattern
projection, comprising:

exposure level determination means for determining
a predetermined exposure level needed by an image
pickup device of the image pickup apparatus; and
shutter speed determination means for determining
a first shutter speed to achieve the predetermined
exposure level determined by the exposure level
determination means in the image pickup without pattern
projection, and a second shutter speed not slower than
the first shutter speed, wherein

the image pickup with pattern projection is conducted by use of the second shutter speed.

15. An image pickup apparatus comprising:

image pickup means, including an image pickup device, for picking up an image of an object;

photometric means for measuring luminance information on the object;

projection means for projecting a pattern on the object during the image pickup, the image pickup apparatus being capable of performing an image pickup by the image pickup means with pattern projection by the projection means on the object to obtain three-dimensional information on the object, and an image pickup by the image pickup means without pattern projection;

exposure level determination means for determining a predetermined exposure level needed by the image pickup device; and

shutter speed determination means for determining a first shutter speed to achieve the predetermined exposure level determined by the exposure level determination means in the image pickup without pattern projection, and a second shutter speed not slower than the first shutter speed, on the basis of luminance information on the object measured by the photometric means, wherein

the image pickup means conducts the image pickup

with pattern projection by the projection means by use
of the second shutter speed.